



FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	ATTY. DOCKET NO. IL920030044US1	SERIAL NO.: 10/699,227
	APPLICANT: Shmuel Ur, et al.	
	FILING DATE: October 31, 2003	GROUP: 2857

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
AA						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AB							

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

SC	AC	Lichtenstein, Yossi et al., "Model Based Test Generation for Processor Verification", Sixth Innovative Applications of Artificial Intelligence Conference, August 1994, pp. 83-94.
SC	AD	Chandra, A. et al., "AVPGEN - A Test Generator for Architecture Verification", IEEE Trans. on Very Large Scale Integration (VLSI) Systems, Vol. 3, No. 2, pp. 188-200 (June 1995).
SC	AE	O'Krafka, Brian et al., "MPTG: A Portable Test Generator for Cache-Coherent Multiprocessors", International Conference on Computers and Communicatins, 1995 IEEE, pp. 38-44.
SC	AF	Bergmann, Jules et al., "Improving Coverage Analysis and Test Generation for Large Designs". Proceedings of the International Conference on Computer Design, pp. 580-583, Nov. 1999.
SC	AG	Seeger, C.J. et al., "Formal Verification by Symbolic Evaluation of Partially-Ordered Trajectories" Formal Methods in System Design: An International Journal, 6(2): 147-189, March 1995.
SC	AH	Edelstein, O., et al., "Multithreaded Java Program Test Generation", IBM Systems Journal, Vol. 41, No. 1, 2002, pp. 111-125.
SC	AI	Stoller, S. et al., "Model-Checking Multi-Threaded Distributed Java Programs", Proceedings of the 7th International SPIN Workshop on Model Checking of Software, pp. 224-244, New York, 2000.

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DATE CONSIDERED

9-16-05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.